

Technical documentation





**TPS2662**

ZHCSI22F – OCTOBER 2017 – REVISED DECEMBER 2021

# **TPS2662x** 具有集成输入和输出反极性保护功能的 **60V 800mA** 工业电子保险丝

# **1** 特性

**72 TEXAS** 

• 工作电压为 4.5V 至 60V, 绝对最大值为 62V

**INSTRUMENTS** 

- 集成反向输入极性保护,低至 –60V
- 集成反向输出极性保护,低至 – (60 – V<sub>IN</sub>) (仅限 TPS26624 和 TPS26625)
- 总 RON 为 478mΩ 的集成背对背 MOSFET
- 25mA 至 880mA 可调节电流限制 (880mA 时精度为 ±5%)
- 使用最少的外部组件在浪涌期间提供负载保护 (IEC 61000-4-5)
- 符合 IEC 61000-4-4 标准的电气快速瞬变抗扰度
- 快速反向电流阻断响应 (0.3µs)
- 可调节 UVLO、OVP 切断、 输出压摆率控制,用于浪涌电流限制
- 38V 固定过压钳位 (仅限 TPS26622 和 TPS26623)
- 低静态电流(工作时为 340µA, 关断时为 12µA)
- 小尺寸 10L (3mm × 3mm) VSON
- 通过 UL 2367 认证
	- 文件编号 169910
	- R<sub>ILIM</sub> ≥ 7.5kΩ (最大电流为 0.91A)
- 通过 IEC 62368-1 认证

# **2** 应用

- PLC I/O 模块
- 交流和伺服驱动器
- 传感器和控制
- 恒温器
- PoE 高侧保护



# **3** 说明

TPS2662x 系列高电压电子保险丝设计紧凑,功能丰 富,且具有一整套保护功能。4.5V 至 60V 的宽电源输 入范围可实现对众多常用直流总线电压的控制。该器件 可以承受并保护由高达 ±60V 的正负电源供电的负载。 TPS26624 和 TPS26625 器件支持输入和输出反极性 保护功能。集成的背对背 FET 可提供反向电流阻断功 能,因此该器件适用于在电源故障和欠压条件下要求保 持输出电压的系统。负载、电源和器件保护具有许多可 调特性,包括过流、输出压摆率和过压、欠压阈值。 TPS2662x 系列内部可靠的保护控制模块以及高额定电 压有助于简化针对浪涌保护的系统设计。

TPS26620、TPS26622 和 TPS26624 具有闭锁功能, TPS26621、TPS26623 和 TPS26625 具有自动重试功 能,用于应对过热和过流故障事件。

这些器件采用 3mm × 3mm 10 引脚 SON 封装,额定 工作温度范围为 –40°C 至 +125°C。





(1) 如需了解所有可用封装,请参阅数据表末尾的可订购产品附 录。



–**60V** 电源时的反向输入极性保护





# **Table of Contents**





# **4 Revision History**

注:以前版本的页码可能与当前版本的页码不同



- Specifications section...5 • Updated the Parameter Measurement Information graph to explain the UVLO\_tREC ..................................... 14 • Updated the *Feature Description* Undervoltage Lockout (UVLO) section to explain the UVLO\_t<sub>REC</sub> timer..... 16
- Updated the *Feature Description* Undervoltage Lockout (UVLO) section ...16
- 







# **5 Device Comparison Table**



# **6 Pin Configuration and Functions**



图 **6-1. DRC Package 10-Pin VSON Top View**

#### 表 **6-1. Pin Functions**





# **7 Specifications**

## **7.1 Absolute Maximum Ratings**



over operating free-air temperature range, all voltages referred to GND (unless otherwise noted) $(1)$ 

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# **7.2 ESD Ratings**



(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

# **7.3 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)





### **7.4 Thermal Information**



(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

# **7.5 Electrical Characteristics**

 $-40^{\circ}$ C  $\leq$  T<sub>A</sub> = T<sub>J</sub>  $\leq$  +125°C, V<sub>(IN)</sub> = 24 V, V<sub>(SHDN)</sub> = 2 V, R<sub>(ILIM)</sub> = 267 k Ω, FLT = OPEN, C<sub>(OUT)</sub> = 1 µF, C<sub>(dVdT)</sub> = OPEN. (All voltages referenced to GND, (unless otherwise noted))



# **7.5 Electrical Characteristics (continued)**

 $-40^{\circ}$ C  $\leq$  T<sub>A</sub> = T<sub>J</sub>  $\leq$  +125°C, V<sub>(IN)</sub> = 24 V, V<sub>(SHDN)</sub> = 2 V, R<sub>(ILIM)</sub> = 267 k Ω, FLT = OPEN, C<sub>(OUT)</sub> = 1 µF, C<sub>(dVdT)</sub> = OPEN. (All voltages referenced to GND, (unless otherwise noted))





# **7.6 Timing Requirements**

 $-40^{\circ}$ C  $\leq$  T<sub>A</sub> = T<sub>J</sub>  $\leq$  +125°C, V<sub>(IN)</sub> = 24 V, V<sub>(SHDN)</sub> = 2 V, R<sub>(ILIM)</sub> = 267 k Ω, FLT = OPEN, C<sub>(OUT)</sub> = 1 µF, C<sub>(dVdT)</sub> = OPEN. (All voltages referenced to GND, (unless otherwise noted))





# **7.6 Timing Requirements (continued)**

 $-40^{\circ}$ C  $\leq$  T<sub>A</sub> = T<sub>J</sub>  $\leq$  +125°C, V<sub>(IN)</sub> = 24 V, V<sub>(SHDN)</sub> = 2 V, R<sub>(ILIM)</sub> = 267 k Ω, FLT = OPEN, C<sub>(OUT)</sub> = 1 µF, C<sub>(dVdT)</sub> = OPEN. (All voltages referenced to GND, (unless otherwise noted))



# **7.7 Typical Characteristics**























图 **8-1. Timing Waveforms**



# **9 Detailed Description**

## **9.1 Overview**

The TPS2662x is a family of high voltage industrial eFuses with integrated back-to-back MOSFETs and enhanced built-in protection circuitry. The device provides robust protection for all systems and applications powered from 4.5 V to 60 V. The device can withstand ±60-V positive and negative supply voltages without damage. The device features fully integrated reverse polarity protection and require zero additional power components. For hot-pluggable boards, the device provides hot-swap power management with in-rush current control. Load, source, and device protections are provided with many programmable features including overcurrent, overvoltage, undervoltage. The precision overcurrent limit (±5% at 880 mA) helps to minimize over design of the input power supply, while the fast response short-circuit protection 220 ns (typical) immediately isolates the faulty load from the input supply when a short circuit is detected.

The internal robust protection control blocks of the TPS2662x along with its ±60-V rating helps to simplify the system designs for the surge compliance ensuring complete protection of the load and the device. TPS2662x devices are immune to noise tests like Electrical Fast Transients that are common in industrial applications and simplifies the system design that require criterion-A performance during this test.

The device provides precise monitoring of voltage bus for brown-out and overvoltage conditions and asserts fault signal for the downstream system. The TPS2662x monitor functions threshold accuracy of ±3% ensures tight supervision of the supply bus, eliminating the need for a separate supply voltage supervisor chip.

The device monitors  $V_{(IN)}$  and  $V_{(OUT)}$  to provide true reverse current blocking when a reverse condition or input power failure condition is detected.



## **9.2 Functional Block Diagram**



# **9.3 Feature Description**

#### **9.3.1 Undervoltage Lockout (UVLO)**

When the voltage at UVLO pin falls below  $V_{(UVLOF)}$  during input power fail or input undervoltage fault, the internal FET quickly turns off and FLT is asserted. The UVLO comparator has a hysteresis of 100 mV. To set the input UVLO threshold, connect a resistor divider network from IN supply to UVLO terminal to RTN as shown in  $\&$  9-1.





图 **9-1. UVLO and OVP Thresholds Set by R1, R2 and R<sup>3</sup>**

If the Undervoltage Lockout function is not needed, the UVLO terminal must be connected to the IN terminal with a 1-MΩ resistor. UVLO pin is 5-V rated and this resistor limits the UVLO pin current to < 60 µA. The UVLO terminal must not be left floating.

#### **9.3.2 Overvoltage Protection (OVP)**

The TPS2662x family incorporate circuitry to protect the system during overvoltage conditions. The TPS26620, TPS26621, TPS26624 and TPS26625 feature overvoltage cut off functionality. A voltage more than  $V_{\text{(OVPR)}}$  on OVP pin turns off the internal FET and protects the downstream load. To program the OVP threshold externally, connect a resistor divider from IN supply to OVP terminal to RTN as shown in  $\boxtimes$  9-1. If the overvoltage feature is not to be used then connect OVP terminal to RTN directly and ensure  $V_{\text{IN}}$  is not exceeded beyond OVP<sub>MAX</sub>.

The TPS26622 and TPS26623 feature an internally fixed 38-V overvoltage clamp (V<sub>OVC</sub>) functionality. The OVP terminal of these devices must be connected to the RTN terminal directly. These devices clamp the output voltage to  $V_{\text{OVC}}$ , when the input voltage exceeds 38 V. During the output voltage clamp operation, the power dissipation in the internal MOSFET is  $P_D = (V_{IN} - V_{OVC}) \times I_{OUT}$ . Excess power dissipation for prolonged period can make the device to enter into thermal shutdown. If the device temperature does not reach  $T_{(TSD)}$ , the device turns off the internal FETs after a delay of  $t_{CL-Dly}$ . After the internal FETs are turned off, TPS26622 latches-off and TPS26623 device auto-retries.  $\boxed{8}$  7-25 illustrates the overvoltage clamp functionality.

#### **9.3.3 Hot Plug-In and Inrush Current Control**

The devices are designed to control the inrush current upon insertion of a card into a live backplane or other hotpower source. This design limits the voltage sag on the backplane's supply voltage and prevents unintended resets of the system power. The controlled start-up also helps to eliminate conductive and radiative interferences. An external capacitor connected from the dVdT pin to RTN defines the slew rate of the output voltage at power-on as shown in  $\overline{8}$  9-2 and Figure 9-3.



(1)



# 图 **9-2. Output Ramp Up Time tdVdT is Set by C(dVdT)**

The dVdT pin can be left floating to obtain a predetermined slew rate  $(t_{dVdT})$  on the output. When the terminal is left floating, the devices set an internal output voltage ramp rate of 24 V/660 µs. A capacitor can be connected from dVdT pin to RTN to program the output voltage slew rate slower than 24 V/660 µs. Use 方程式 1 and 方程  $\vec{\pi}$  2 to calculate the external C<sub>(dVdT)</sub> capacitance.

方程式 1 governs slew rate at start-up.

$$
I_{(dVdT)} = \left(\frac{C_{(dVdT)}}{Gain_{(dVdT)}}\right) \times \left(\frac{dV_{(OUT)}}{dt}\right)
$$

where

- $I_{(dVdT)} = 1.98 \mu A$  (typical) dV (OUT)
- dt = Desired output slew rate
- Gain<sub>(dVdT)</sub> = dVdT to V<sub>OUT</sub> gain = 24.6

The total ramp time ( $t_{dVdT}$ ) of  $V_{(OUT)}$  for 0 to  $V_{(IN)}$  can be calculated using 方程式 2.

 $t_{dVdT} = 20.5 \times 10^3 \times V_{(IN)} \times C_{(dVdT)}$  (2)



图 **9-3. Hot Plug-In and Inrush Current Control at 24-V Input**

# **9.3.4 Reverse Polarity Protection**

# *9.3.4.1 Input Side Reverse Polarity Protection*

TPS2662x eFuses feature fully integrated input side reverse polarity protection. The internal FETs of the eFuse turn OFF during the input reverse polarity event and protect the downstream loads from negative supply voltages that can appear due to field mis-wiring on the input power terminals. Figure 9-4 illustrates the reverse input polarity protection functionality.



图 **9-4. Reverse Input Supply Protection at** –**60 V**

# *9.3.4.2 Output Side Reverse Polarity Protection*

TheTPS26624 and TPS26625 eFuses feature fully integrated input as well as output reverse polarity protection. The internal FETs of the eFuse turn OFF during the output reverse polarity event and protects the upstream circuits from negative voltage that can appear at the output of the eFuse due to field miswiring at the output side with an external isolated power supplies.  $\boxtimes$  9-5 illustrates the performance during output side reverse polarity event with V<sub>(IN)</sub> un-powered and 图 9-6 illustrates the performance with V<sub>(IN)</sub> powered. 图 9-7 illustrates the output recovery performance after the reverse polarity is removed.





图 **9-5. Reverse Output Polarity Protection With** –**60 V at OUT and VIN = 0 V**



#### **9.3.5 Overload and Short-Circuit Protection**

The device monitors the load current by sensing the voltage across the internal sense resistor. The FET current is monitored during start-up and normal operation.

#### *9.3.5.1 Overload Protection*

Connect a resistor across ILIM to RTN to program the over load current limit  $I_{(OL)}$ . During overload conditions, the device regulates the current through it at  $I_{(OL)}$  programmed by the R<sub>(ILIM)</sub> resistor as shown in 方程式 3 for a maximum duration of  $t_{CL(dly)}$ .

$$
I_{OL} = \frac{6.636}{R_{ILIM}}
$$

where

(3)

- $\cdot$  I<sub>(OL)</sub> is the overload current limit in Ampere
- $R_{(ILIM)}$  is the current limit resistor in k Ω

During the current limit operation the output voltage droops and this can cause the device to hit the thermal shutdown threshold  $T_{(TSD)}$  before t<sub>CL(dly)</sub> time. After the thermal shutdown threshold is hit or t<sub>CL(dly)</sub> is elapsed,



the internal FETs of TPS2662x turns OFF. FETs in TPS26620, TPS26622 and TPS26624 remain OFF and latched. To reset the latch, cycle the  $\overline{\text{SHDN}}$  or UVLO, or recycle the V<sub>IN</sub>. TPS26621, TPS26623 and TPS26625 commence an auto-retry cycle after a retry time of 512 msec. The internal FETs turn back on in dVdT mode after this retry time. If the overload still exists, then the device regulates the current at programmed current limit,  $I_{(OL)}$ . t<sub>CL(dly)</sub> is the maximum duration for current limiting and estimated as t<sub>CL(dly)</sub> = 512 ms + [3.3 × C<sub>dVdT</sub> / 2 µ A]  $(C_{dVdT}$  in  $nF$ ).



#### *9.3.5.2 Short-Circuit Protection*

During a transient output short circuit event, the current through the device increases rapidly. As the current-limit amplifier cannot respond quickly to this event due to its limited bandwidth, the device incorporates a fast-trip comparator. The fast-trip comparator architecture is designed for fast turn OFF ( $t_{FAST-TRIP(dly)}$  = 220 ns (typical)) of the internal FET during an output short circuit event. The fast-trip threshold is internally set to I<sub>(FAST-TRIP)</sub>. The fast-trip circuit holds the internal FET off for only a few microseconds, after which the device turns back on slowly, allowing the current-limit loop to regulate the output current to  $I_{(OL)}$ . Then the device functions similar to the overload condition. Figure 9-10 and Figure 9-11 illustrate the behavior of the system during output shortcircuit condition.

![](_page_21_Picture_1.jpeg)

![](_page_21_Figure_2.jpeg)

The fast-trip comparator architecture has a supply line noise immunity resulting in a robust performance in noisy environments. This feature is achieved by controlling the turn OFF time of the internal FET based on the differential voltage across V<sub>(IN)</sub> and V<sub>(OUT)</sub> after the current through the device exceeds I<sub>(FAST-TRIP)</sub>. Higher the voltage difference  $V_{(IN)} - V_{(OUT)}$ , faster the turn OFF time,  $t_{FAST-TRIP(dly)}$ .

#### **9.3.5.2.1 Start-Up With Short-Circuit On Output**

When the device is started with short-circuit on the output, it limits the load current to the current limit,  $I_{(OL)}$ , and functions similar to the overload condition. Figure 9-12 illustrates the function of the device in this condition. This feature helps in quick isolation of the fault and ensures stability of the DC bus.

![](_page_21_Figure_6.jpeg)

![](_page_21_Figure_7.jpeg)

#### **9.3.6 Reverse Current Protection**

The device monitors  $V_{(IN)}$  and  $V_{(OUT)}$  to provide true reverse current blocking when a reverse condition or input power failure condition is detected. The reverse comparator turns OFF the internal FET within 310 ns (typical) as

![](_page_22_Picture_0.jpeg)

soon as  $V_{(IN)} - V_{(OUT)}$  falls below - 2.6 V. The reverse comparator turns on within 63 µs (typical) after the differential forward voltage V<sub>(IN)</sub> - V<sub>(OUT)</sub> exceeds 115 mV. 图 9-13 and 图 9-14 illustrate the behavior of the system during input hot short circuit condition.

![](_page_22_Figure_3.jpeg)

The reverse comparator architecture has a supply line noise immunity resulting in a robust performance in noisy environments. This feature is achieved by controlling the turn OFF time of the internal FET based on the overdrive differential voltage V<sub>(IN)</sub> - V<sub>(OUT)</sub> over V<sub>(REVTH)</sub>. Higher the over-drive, faster the turn OFF time, t<sub>REV(dly)</sub>. Figure 7-22 shows the reverse current blocking response time versus over-drive voltage.

#### **9.3.7 FAULT Response**

The FLT open-drain output asserts (active low) under the following conditions:

- Fault events such as undervoltage, overvoltage, over load, reverse current and thermal shutdown conditions
- The device enters low current shutdown mode when SHDN is pulled low
- During start-up when the internal FET GATE is not fully enhanced

The device is designed to eliminate false reporting by using an internal *de-glitch* circuit for fault conditions without the need for an external circuitry.

The FLT signal can also be used as a Power Good indicator to the downstream loads like DC/DC converters. An internal Power Good (PGOOD) signal is ORd with the fault logic. During start-up, when the device is operating in dVdT mode, PGOOD and FLT it remains low and is de-asserted after the dVdT mode is completed and the internal FET is fully enhanced. The PGOOD signal has deglitch time incorporated to ensure that internal FET is fully enhanced before heavy load is applied by the downstream converters. Rising deglitch delay is determined by t<sub>PGOOD(degl)</sub> = Maximum {(750 + 573× C<sub>(dVdT)</sub>), t<sub>PGOODR</sub>}, where C<sub>(dVdT)</sub> is in nF and t<sub>PGOOD(degl)</sub> is in µs. FLT can be left open or connected to RTN when not used.  $V_{(IN)}$  falling below 3.4 V resets FLT.

#### **9.3.8 IN, OUT, RTN, and GND Pins**

TI recommends a ceramic bypass capacitor close to the device from IN to GND to alleviate bus transients. The recommended input operating voltage range is 4.5 to 60 V. V<sub>(OUT)</sub>, in the ON condition, is calculated using 方程 式 4.

$$
V\left(\text{OUT}\right) = V\left(\text{IN}\right) - \left(\text{RON} \times I\left(\text{OUT}\right)\right)
$$

Where,

• RON is the total ON resistance of the internal FETs.

(4)

![](_page_23_Picture_1.jpeg)

GND pin must be connected to the system ground. RTN is the device ground reference for all the internal control blocks. Connect the TPS2662x family support components: R<sub>(ILIM)</sub>, C<sub>(dVdT)</sub> and resistors for UVLO and OVP with respect to the RTN pin. Internally, the device has reverse input polarity protection block between RTN and the GND terminal. Connecting RTN pin to GND pin disables the reverse polarity protection feature and the TPS2662x gets permanently damaged when operated under this fault event.

#### **9.3.9 Thermal Shutdown**

The device has a built-in overtemperature shutdown circuitry designed to protect the internal FETs, if the junction temperature exceeds  $T_{(TSD)}$ . After the thermal shutdown event, depending upon the mode of fault response, the device either latches off or commences an auto-retry cycle 512 ms after T」<  $(T_{(TSD)}$  - 13.5°C). During the thermal shutdown, the fault pin FLT pulls low to indicate a fault condition.

# **9.4 Device Functional Modes**

### **9.4.1 Low Current Shutdown Control (SHDN)**

The internal FETs and the load current can be switched off by pulling the SHDN pin below 0.9-V threshold with a micro-controller GPIO pin or can be controlled remotely with an opto-isolator device as shown in  $\boxtimes$  9-15 and  $\boxtimes$ 9-16. The device quiescent current reduces to 10  $\mu$  A (typical) in SHUTDOWN state. To assert SHDN low, the pull down must sink at least 10 µA at 400 mV. To enable the device, SHDN must be pulled up to at least 1.8 V. After the device is enabled, the internal FETs turn on with dVdT mode.

![](_page_23_Figure_8.jpeg)

![](_page_24_Picture_0.jpeg)

# **10 Application and Implementation**

备注

以下应用部分中的信息不属于 TI 器件规格的范围,TI 不担保其准确性和完整性。TI 的客 户应负责确定 器件是否适用于其应用。客户应验证并测试其设计,以确保系统功能。

### **10.1 Application Information**

The TPS2662x family is an industrial eFuse, typically used for Hot-Swap and power rail protection applications. The device operates from 4.5 V to 60 V with programmable current limit, overvoltage, undervoltage and reverse polarity protections. The device aids in controlling inrush current and provides robust protection against reverse current and field miss-wiring conditions for systems such as PLC I/O modules and sensor power supplies. The device also provides robust protection for multiple faults on the system rail.

The *Detailed Design Procedure* section can be used to select component values for the device.

Alternatively, the *WEBENCH*® software can be used to generate a complete design. The WEBENCH® software uses an iterative design procedure and accesses a comprehensive database of components when generating a design. Additionally, a spreadsheet design tool, *TPS2662 Design Calculator*, is available in the web product folder.

### **10.2 Typical Application**

![](_page_24_Figure_10.jpeg)

![](_page_24_Figure_11.jpeg)

#### **10.2.1 Design Requirements**

 $\bar{\textbf{\#}}$  10-1 shows the design requirements for TPS2662x.

![](_page_24_Picture_299.jpeg)

![](_page_24_Picture_300.jpeg)

![](_page_25_Picture_1.jpeg)

#### **10.2.2 Detailed Design Procedure**

#### *10.2.2.1 Step-by-Step Design Procedure*

To begin the design process, the designer must know the following parameters:

- Input operating voltage range
- Maximum output capacitance
- Maximum current limit
- Load during start-up
- Maximum ambient temperature

This design procedure below seeks to control junction temperature of the device in both steady state and start-up conditions by proper selection of the output ramp-up time and associated support components. The designer can adjust this procedure to fit the application and design criteria.

#### *10.2.2.2 Programming the Current Limit Threshold R(ILIM) Selection*

The R<sub>(ILIM)</sub> resistor at the ILIM pin sets the over load current limit. the current limit can be set using 方程式 5.

$$
R_{ILIM} = \frac{6.636}{I_{LIM}} = 13.27 k\Omega
$$
 (5)

where

•  $I_{LIM}$  = 500 mA

Choose the closest standard 1% resistor value:  $R_{(ILIM)} = 13.3 \text{ k}\Omega$ .

#### *10.2.2.3 Undervoltage Lockout and Overvoltage Set Point*

The undervoltage lockout (UVLO) and overvoltage trip point are adjusted using an external voltage divider network of  $R_1$ ,  $R_2$  and  $R_3$  connected between IN, UVLO, OVP and RTN pins of the device. The values required for setting the undervoltage and overvoltage are calculated by solving 方程式 6 and 方程式 7.

$$
V(\text{OVPR}) = \frac{R_3}{R_1 + R_2 + R_3} \times V(\text{OV})
$$
(6)  

$$
V(\text{UVLOR}) = \frac{R_2 + R_3}{R_1 + R_2 + R_3} \times V(\text{UV})
$$
(7)

For minimizing the input current drawn from the power supply  $\{I_{(R123)} = V_{(IN)}/(R_1+R_2+R_3)\}$ , TI recommends to use higher value resistance for  $R_1$ ,  $R_2$  and  $R_3$ .

However, the leakage current due to external active components connected at resistor string can add error to these calculations. So, the resistor string current,  $I(R_{123})$  must be chosen to be 20 times greater than the leakage current of UVLO and OVP pins.

From the device electrical specifications,  $V_{\text{(OVPR)}}$  = 1.19 V and  $V_{\text{(UVLOR)}}$  = 1.19 V. From the design requirements, V<sub>(OV)</sub> is 30 V and V<sub>(UV)</sub> is 18 V. To solve the equation, first choose the value of R<sub>3</sub> = 30.1 kΩ and use 方程式 6 to solve for  $(R_1 + R_2)$  = 728.7 kΩ. Use 方程式 7 and value of  $(R_1 + R_2)$  to solve for  $R_2$  = 20.05 kΩ and finally R<sub>1</sub>= 708.6 kΩ.

Choose the closest standard 1% resistor values:  $R_1 = 715$  k $\Omega$ ,  $R_2 = 20$  k $\Omega$ , and  $R_3 = 30.1$  k $\Omega$ .

#### *10.2.2.4 Setting Output Voltage Ramp Time*—*(tdVdT)*

For a successful design, the junction temperature of the device must be kept below the absolut -maximum rating during dynamic (start-up) and steady state conditions. The dynamic power dissipation is often an order magnitude greater than the steady state power dissipation. It is important to determine the right start-up time and the inrush current limit for the system to avoid thermal shutdown during start-up with and without load. The rampup capacitor  $C_{\text{ddV}}$  is calculated considering the two possible cases:

#### **10.2.2.4.1 Case 1: Start-Up Without Load**—**Only Output Capacitance C(OUT) Draws Current During Start-Up**

During start-up, as the output capacitor charges, the voltage difference across the internal FET decreases, and the power dissipation decreases. Typical ramp-up of the output voltage, inrush current and instantaneous power dissipated in the device during start-up are shown in Figure 10-2. The average power dissipated in the device during start-up is equal to the area of triangular plot (red curve in Figure 10-3) averaged over  $t_{\text{dVdT}}$ .

![](_page_26_Figure_5.jpeg)

The inrush current is determined as shown in 方程式 8.

$$
I=C\times\frac{dV}{dT}\geq I(\text{INRUSH})=C(\text{OUT})\times\frac{V(\text{IN})}{t\text{dVdT}}
$$

Average power dissipated during start-up is given by 方程式 9.

 $P_D$ (INRUSH) =  $0.5 \times V$ (IN)  $\times$  (INRUSH)

方程式 9 assumes that the load does not draw any current until the output voltage reaches its final value.

#### **10.2.2.4.2 Case 2: Start-Up With Load** —**Output Capacitance C(OUT) and Load Draws Current During Start-Up**

When the load draws current during the turn-on sequence, additional power is dissipated in the device. Considering a resistive load RL(SU) during start-up, typical ramp-up of output voltage, Figure 10-4 shows load current and the instantaneous power dissipation in the device. Figure 10-5 plots Instantaneous power dissipation with respect to time.

(8)

(9)

![](_page_27_Picture_0.jpeg)

![](_page_27_Figure_2.jpeg)

The additional power dissipation during start-up is calculated using  $f \# \vec{x}$  10.

$$
P_D(LOAD) = \frac{1}{6} \times \frac{V(n)^2}{R L(SU)}
$$
\n(10)

Total power dissipated in the device during start-up is given by 方程式 11.

 $P$  D(STARTUP) =  $P$  D(INRUSH) +  $P$  D(LOAD) (11)

Total current during start-up is given by 方程式 12.

$$
I(\text{STARTUP}) = I(\text{INRUSH}) + I_{L(t)}
$$

For the design example under discussion,

Select the inrush current  $I_{(INRUSH)} = 0.1 A$  and  $t_{dVdT}$  calculated using 方程式 8 is 5.28 ms.

For a given start-up time, C<sub>dVdT</sub> capacitance value calculated using 方程式 2 is 10.7 nF for t<sub>dVdT</sub> = 5.28 ms and  $V_{IN}$  = 24 V.

Choose the closest standard value: 10.0 nF and 16-V capacitor.

(12)

![](_page_28_Picture_0.jpeg)

The inrush power dissipation due to output capacitor alone is calculated using 方程式 9 and it is 1.2 W. Considering the start-up with 96-Ω load, the additional power dissipation calculated using 方程式 10 is 1 W. The total device power dissipation during start-up is 2.2 W

The power dissipation with or without load, for a selected start-up time must not exceed the thermal shutdown limits as shown in  $\overline{8}$  10-6.

From the thermal shutdown limit graph, at  $T_A$  = 125°C, thermal shutdown time for 2.2 W is close to 580 ms. It is safe to have a minimum 30% margin to allow for variation of the system parameters such as load, component tolerance, input voltage and layout. Selected 10-nF C<sub>dVdT</sub> capacitor and 5.28-ms start-up time (t<sub>dVdT</sub>) are well within the limit for successful start-up with 96-Ω load.

Higher value  $C_{(dVdT)}$  capacitor can be selected to further reduce the power dissipation during start-up.

![](_page_28_Figure_6.jpeg)

图 **10-6. Thermal Shutdown Time vs Power Dissipation**

#### **10.2.2.4.3 Support Component Selections** – **RFLT and C(IN)**

The R<sub>FLT</sub> Absolute Maximum Ratings serves as pull-up for the open-drain fault output. The current sink by this pin must not exceed 10 mA (see the *Absolute Maximum Ratings* table). TI recommends typical resistance value in the range of 10 kΩ to 100 kΩ for R<sub>FLT</sub>. The C<sub>IN</sub> is a local bypass capacitor to suppress noise at the input. TI recommends typical capacitance value in the range of 0.1  $\mu$ F to 1  $\mu$ F for C<sub>(IN)</sub>.

![](_page_29_Picture_1.jpeg)

#### **10.2.3 Application Curves**

![](_page_29_Figure_3.jpeg)

![](_page_30_Picture_0.jpeg)

# **10.3 System Examples**

#### **10.3.1 Field Supply Protection in PLC, DCS I/O Modules**

![](_page_30_Figure_4.jpeg)

图 **10-13. Power Delivery Circuit Block Diagram in I/O Modules**

The PLC or Distributed Control System (DCS) I/O modules are often connected to an external field power supply to support higher power requirements of the field loads like sensors and actuators. Power-supply faults or miswiring can damage the loads or cause the loads not to operate correctly. The TPS26624 and TPS26625 can be used as a front end protection circuit to protect and provide stable supply to the field loads. Undervoltage, overvoltage, and input and output side reverse polarity protection features of these devices prevent the loads to experience voltages outside the operating range, which can permanently damage the loads.

Field power supply is often connected to multiple I/O modules that can deliver more current than a single I/O module can handle. Overcurrent protection scheme of the TPS2662x family limits the current from the power supply to the module so that the maximum current does not rise above what the board is designed for. Fast short-circuit protection scheme isolates the faulty load from the field supply quickly and prevents the field supply to dip and cause interrupts in the other I/O modules connected to the same field supply. High accurate (±5% at 0.88 A) current limit facilitates more I/O modules to be connected to field supply. Fault indication ( FLT) features facilitate continuous load monitoring.

The TPS26624 and TPS26625 also acts as a smart diode with protection against reverse current during output side miswiring. Reverse current can potentially damage the field power supply and cause the I/O modules to run hot or can cause permanent damage.

If the field power supply is connected in reverse polarity on the input side (which is not unlikely as field power supplies are usually connected with screw terminals), field loads can permanently get damaged due to the reverse voltage. Also, during the installation the field power supply can be miswired on the output side instead of on the input side which can damage the upstream power supply and electronics. The input and output reverse polarity protection feature of the TPS26624 and TPS26625 prevents the reverse voltage to appear at the load side as well as supply side offering complete system protection during field miswiring.

![](_page_31_Picture_1.jpeg)

#### **10.3.2 Simple 24-V Power Supply Path Protection**

With the TPS2662x, a simple 24-V power supply path protection can be realized using a minimum of four external components as shown in the schematic diagram in  $\boxtimes$  10-14. The external components required are: a 1Meg  $\Omega$  R<sub>(1)</sub> resistor across IN and UVLO pins, a R<sub>(ILIM)</sub> resistor to program the current limit, C<sub>(IN)</sub> and C<sub>(OUT)</sub> capacitors.

![](_page_31_Figure_4.jpeg)

图 **10-14. TPS2662x Configured for a Simple 24-V Supply Path Protection**

Protection features with this configuration include:

- Load and device protection from reverse input polarity fault down to  $-60$  V
- Upstream supply and device protection from reverse output polarity fault down to  $-$  (60 VIN) V with TPS26624 and TPS26625 variants
- Protection from 60 V from the external SELV supply: overvoltage Clamp at 38 V with TPS26622 and TPS26623 variants
- Inrush current control with 24 V and 660-µs output voltage slew rate
- Reverse Current Blocking
- Accurate current limiting with auto-retry with TPS26621, TPS26623, TPS26625 variants
- Accurate current limiting with latch-off with TPS26620, TPS26622, TPS26624 variants

#### **10.3.3 Power Stealing in Smart Thermostat**

The adjustable protection features of the TPS2662x eFuse, like the inrush current limiting, overvoltage and overcurrent protection, simplifies the input power management design in smart thermostats. Refer to the TI Design report, *Power Stage Reference Design for Power Stealing Thermostat*, for further information.

#### **10.4 Do's and Don'ts**

- Do not connect RTN to GND. Connecting RTN to GND disables the Reverse Polarity protection feature.
- Do connect the TPS2662x support components  $R_{(ILIM)}$ ,  $C_{(dVdT)}$ , and UVLO, OVP resistors with respect to RTN pin.
- Do connect device PowerPAD to the RTN plane for an enhanced thermal performance.

![](_page_32_Picture_0.jpeg)

# **11 Power Supply Recommendations**

The TPS2662x eFuse is designed for the supply voltage range of 4.5 V  $\leq$  V<sub>IN</sub>  $\leq$  60 V. If the input supply is located more than a few inches from the device, TI recommends an input ceramic bypass capacitor higher than 0.1  $\mu$  F. Power supply must be rated higher than the current limit set to avoid voltage droops during overcurrent and shor-circuit conditions.

#### **11.1 Transient Protection**

In case of short circuit and over load current limit, when the device interrupts current flow, input inductance generates a positive voltage spike on the input and output inductance generates a negative voltage spike on the output. The peak amplitude of voltage spikes (transients) depends on the value of inductance in series to the input or output of the device. These transients can exceed the *Absolute Maximum Ratings* of the device if steps are not taken to address the issue.

Typical methods for addressing transients include:

- Minimizing lead length and inductance into and out of the device
- Using large PCB GND plane
- Use of a Schottky diode across the output and GND to absorb negative spikes in the designs with TPS26620, TPS26621, TPS26622, TPS26623 devices and a TVS clamp in the designs withTPS26624 and TPS26625 devices
- A low value ceramic capacitor ( $C_{(IN)}$  to approximately 0.1  $\mu$  F) to absorb the energy and dampen the transients.

The approximate value of input capacitance can be estimated with 方程式 13.

$$
V_{spike(Absolute)} = V_{(IN)} + I_{(Load)} \times \sqrt{\frac{L_{(IN)}}{C_{(IN)}}}
$$
\n(13)

where

- $V_{(IN)}$  is the nominal supply voltage
- $I_{(LOAD)}$  is the load current
- $L_{(IN)}$  equals the effective inductance seen looking into the source
- $C_{(1N)}$  is the capacitance present at the input

Some applications can require additional Transient Voltage Suppressor (TVS) to prevent transients from exceeding the *Absolute Maximum Ratings* of the device. These transients can occur during positive and negative surge tests on the supply lines. In such applications TI recommends to place at least 1 µF of input capacitor to limit the falling slew rate of the input voltage within a maximum of 20 V/µs.

The circuit implementation with optional protection components (a ceramic capacitor, TVS and Schottky diode) is shown in Figure 11-1 and Figure 11-2.

![](_page_33_Picture_1.jpeg)

![](_page_33_Figure_2.jpeg)

\* Optional components needed for suppression of transients

#### 图 **11-1. Circuit Implementation With Optional Protection Components for TPS26620, TPS26621, TPS26622, and TPS26623**

![](_page_33_Figure_5.jpeg)

\* Optional components needed for suppression of transients

#### 图 **11-2. Circuit Implementation With Optional Protection Components for TPS26624 and TPS26625**

![](_page_34_Picture_0.jpeg)

![](_page_34_Picture_1.jpeg)

# **12 Layout**

# **12.1 Layout Guidelines**

- For all the applications, TI recommends a 0.1 µF or higher value ceramic decoupling capacitor between IN terminal and GND.
- The optimum placement of decoupling capacitor is closest to the IN and GND terminals of the device. Care must be taken to minimize the loop area formed by the bypass-capacitor connection, the IN terminal, and the GND terminal of the IC. See  $\&$  12-1 for a typical PCB layout example.
- High current carrying power path connections must be as short as possible and must be sized to carry at least twice the full-load current.
- RTN, which is the reference ground for the device must be a copper plane or island.
- Locate all the TPS2662x family support components R<sub>(ILIM)</sub>, C<sub>(dVdT)</sub>, UVLO, OVP resistors close to their connection pin. Connect the other end of the component to the RTN with shortest trace length.
- The trace routing for the R<sub>ILIM</sub> component to the device must be as short as possible to reduce parasitic effects on the current limit and current monitoring accuracy. These traces must not have any coupling to switching signals on the board.
- Protection devices such as TVS, snubbers, capacitors, or diodes must be placed physically close to the device they are intended to protect, and routed with short traces to reduce inductance. For example, TI recommends a protection Schottky diode to address negative transients due to switching of inductive loads, and it must be physically close to the OUT and GND pins.
- Thermal considerations: when properly mounted, the PowerPAD package provides significantly greater cooling ability. To operate at rated power, the PowerPAD must be soldered directly to the board RTN plane directly under the device. Other planes, such as the bottom side of the circuit board can be used to increase heat sinking in higher current applications. Designs that do not need reverse input polarity protection can have RTN, GND and PowerPAD connected together. PowerPAD in these designs can be connected to the PCB ground plane.

![](_page_35_Figure_0.jpeg)

图 **12-1. Typical PCB Layout Example With a 2 Layer PCB**

![](_page_36_Picture_0.jpeg)

# **13 Device and Documentation Support**

#### **13.1 Documentation Support**

#### **13.1.1 Related Documentation**

• Texas Instruments, *Power Stage Reference Design for Power Stealing Thermostat* design guide

### **13.2** 接收文档更新通知

要接收文档更新通知,请导航至 ti.com 上的器件产品文件夹。点击*订阅更新* 进行注册,即可每周接收产品信息更 改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

## **13.3** 支持资源

TI E2E™ 支持论坛是工程师的重要参考资料,可直接从专家获得快速、经过验证的解答和设计帮助。搜索现有解 答或提出自己的问题可获得所需的快速设计帮助。

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#### **13.5 Electrostatic Discharge Caution**

![](_page_36_Picture_15.jpeg)

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

# **13.6** 术语表

TI 术语表 本术语表列出并解释了术语、首字母缩略词和定义。

#### **14 Mechanical, Packaging, and Orderable Information**

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

![](_page_37_Picture_0.jpeg)

# **PACKAGING INFORMATION**

![](_page_37_Picture_412.jpeg)

**(1)** The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

![](_page_38_Picture_0.jpeg)

# **PACKAGE OPTION ADDENDUM**

**(3)** MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

**(4)** There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

**(5)** Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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**TEXAS** 

## **TAPE AND REEL INFORMATION**

**ISTRUMENTS** 

![](_page_39_Figure_4.jpeg)

![](_page_39_Figure_5.jpeg)

#### **QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**

![](_page_39_Figure_7.jpeg)

![](_page_39_Picture_526.jpeg)

![](_page_40_Picture_0.jpeg)

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# **PACKAGE MATERIALS INFORMATION**

![](_page_40_Figure_4.jpeg)

![](_page_40_Picture_257.jpeg)

# **GENERIC PACKAGE VIEW**

# **DRC 10 VSON - 1 mm max height**

**3 x 3, 0.5 mm pitch** PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

![](_page_41_Picture_6.jpeg)

![](_page_41_Picture_7.jpeg)

![](_page_42_Picture_1.jpeg)

# **PACKAGE OUTLINE**

# **DRC0010J VSON - 1 mm max height**

PLASTIC SMALL OUTLINE - NO LEAD

![](_page_42_Figure_5.jpeg)

NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.

3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.

![](_page_42_Picture_10.jpeg)

# **EXAMPLE BOARD LAYOUT**

# **DRC0010J VSON - 1 mm max height**

PLASTIC SMALL OUTLINE - NO LEAD

![](_page_43_Figure_4.jpeg)

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

![](_page_43_Picture_8.jpeg)

# **EXAMPLE STENCIL DESIGN**

# **DRC0010J VSON - 1 mm max height**

PLASTIC SMALL OUTLINE - NO LEAD

![](_page_44_Figure_4.jpeg)

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

![](_page_44_Picture_7.jpeg)

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